

**Search Notes**

Application/Control No.

10/814,266

Examiner

Thien F. Tran

Applicant(s)/Patent under  
Reexamination

KATSUMATA ET AL.

Art Unit

2811

**SEARCHED**

Class	Subclass	Date	Examiner
257	336, 344	1/19/2005	TT
257	408, 900	1/19/2005	TT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR